TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c))			Docket No. BUR920030092US1				
In Re Application Allen & al.							
Serial I 10/604,98	iling	Date 8/2003	Examiner Unknown		Group Art Unit Unknown		
Title: The Use of a Layout-Optimization Tool to Increase the Yield and Reliability of VLSI Designs							
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Address to: Assistant Commissioner for Patents Washington, D.C. 20231							
		37 (	CFR 1.97(b)				
1.  The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.							
	37 CFR 1.97(c)						
2.  The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:							
☐ the statement specified in 37 CFR 1.97(e);							
OR							
	ne fee set forth in 37 CF	R 1.17(p).					
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TRANSMITTAL OI	Docket No. BUR920030092US1								
In Re Application: Allen et al.									
Serial No.			Group Art Unit						
10/604,987	08/28/2003	Unknown	Unknown						
The Use of a Layout-Optimization Tool to Increase the Yield and Reliability of VLSI Designs									
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as described belo  Charge the Credit any Charge and Certificate of 1	ount of is atta mmissioner is hereby authorized w. A duplicate copy of this shee le amount of y overpayment. ny additional fee required.  Fransmission by Facsimile*  rant and authorization to charge deposit nile transmitted to the United States	to charge and credit Deposit A t is enclosed.  Certificate of Mailing  Lentify that this document a	, by First Class Mail						
Patent and Trademark C		as first class mail under 37 C.F.R. 1.8 and is addressed to the Assistant Commissioner for Patents, Washington, D.O. 20231 Alexandria, U.A. 223(3.)  Signature of Person Mailing Correspondence  C. MUEZLEN							
	Signature								
Typed or Printed N	ame of Person Signing Certificate	Typed or Printed Name of Person Mailing Certificate							
Treb Coured		Dated: వెల్లూడ్. 9,200	3						



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In repatent application of

Allen et al.

Serial No.: Not Yet Assigned 10/604, 987

Group Art Unit: Not Yet Assigned

Filing Date: Concurrently Herewith 08/28/2003 Examiner: Unknown

THE USE OF A LAYOUT-OPTIMIZATION TOOL TO INCREASE THE YIELD For:

AND RELIABILITY OF VLSI DESIGNS

Commissioner of Patents P.O. Box 1450 Alexandria, VA 22313-1450

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicants' duty of disclosure under 37 CFR §1.56, applicants respectfully bring the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 09-0456.

Respectfully submitted

Frederick W. Gibb, III Registration No. 37,629

McGinn & Gibb, PLLC 2568-A Riva Road, Suite 304 Annapolis, Maryland 21401 (301) 261-8071 Customer No. 29154

ATTY DOCKET NO. SERIAL NO. BUR920030092US1 Not Yet Assigned INFORMATION DISCLOSURE CITATION 15.200 (Use several sheets if necessary) GROUP FILING Concurrently Herewith Unknown TRADEM! U.S. PATENT DOCUMENTS FILING DATE \*EXAMINER SUBCLASS DOCUMENT NUMBER DATE NAME CLASS IF APPROPRIATE INITIA FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT NUMBER DATE COLINTRY CLASS SUBCLASS YES DE3326427 02/13/85 Germany OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Allan et al., "Automated Redundant Via Placement for Increased Vield and Reliability", Proceedings of the SPIE - The International Society for Optical Engineering Conference, vol. 3216, 1997, pp. 114-125. Frank et al., "Yield Improvement of Wafer-Scale Integrated Systolic Structures Via Redundancy", 16th Annual IEEE Electronics and Aerospace Systems Conference and Exposition. 1983, pp. 317-322.

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE CONSIDERED

EXAMINER

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	IBM Technical Disclosu 1, 1985, pp. 36-42.		bility Enhancement Via Redu	-		afers, " vol. 28,	No.	
	Chen et al., "Layout Te	chniques for VLSI Y	ield Enhancement", Proceed , 2001, pp. 140-147.	ings of the SPIE	The Internat	ional Society for	r	
	Optical Engineering Co	nterence'', vol. 4600	, 2001, pp. 140-147. ,					
EXAMINER			DATE CONSIDERED					
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